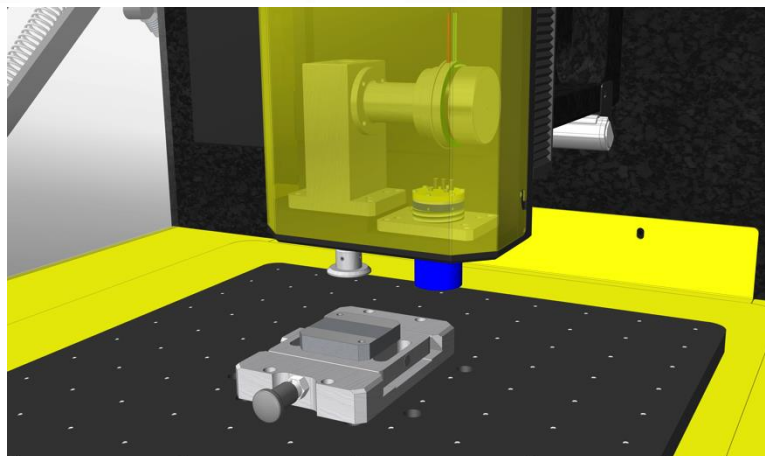
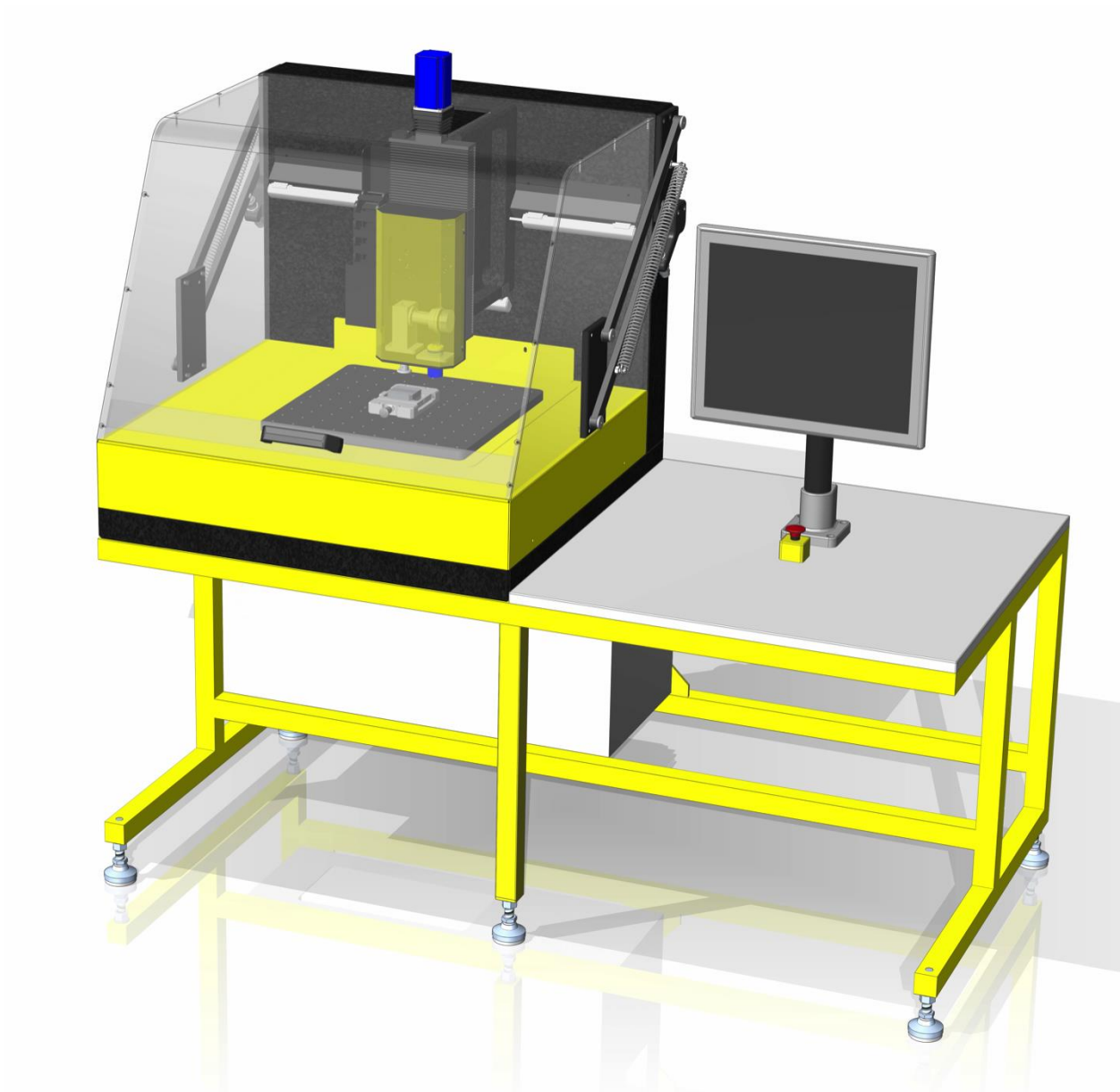
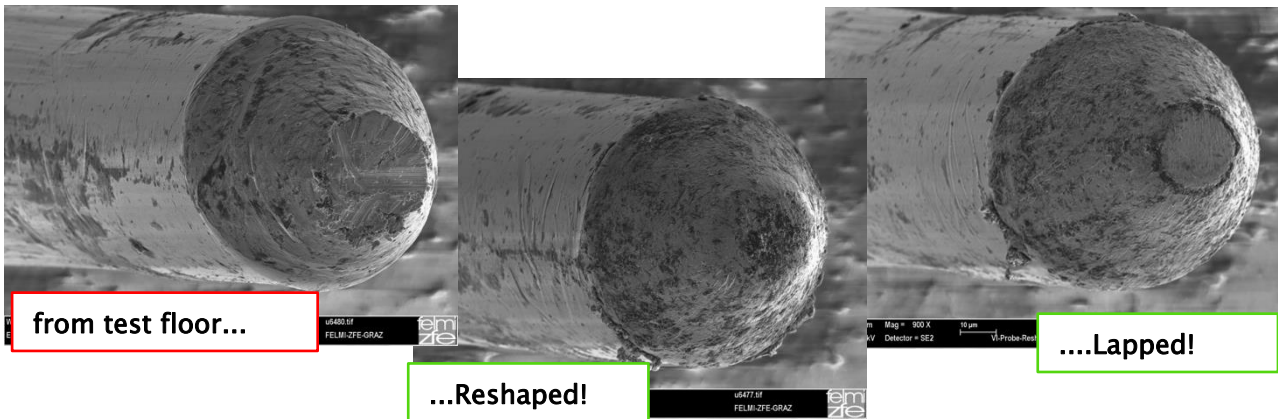


TIPS Probe Refresher TPR-HD "Heavy Duty"

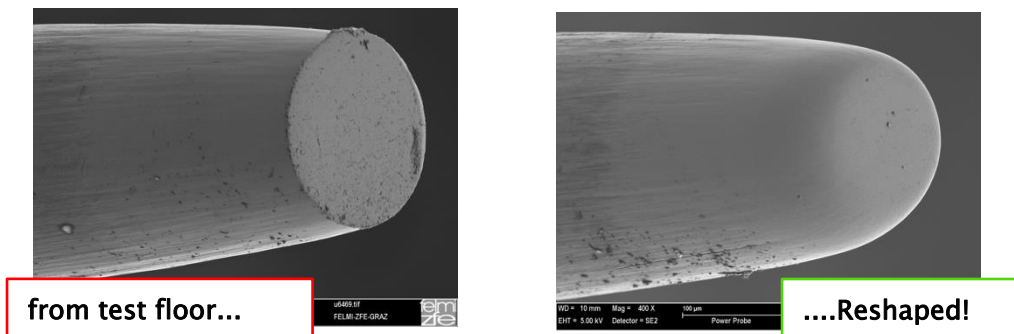


Probe Tip Shape Control & "Doubling Probecard Lifetime"

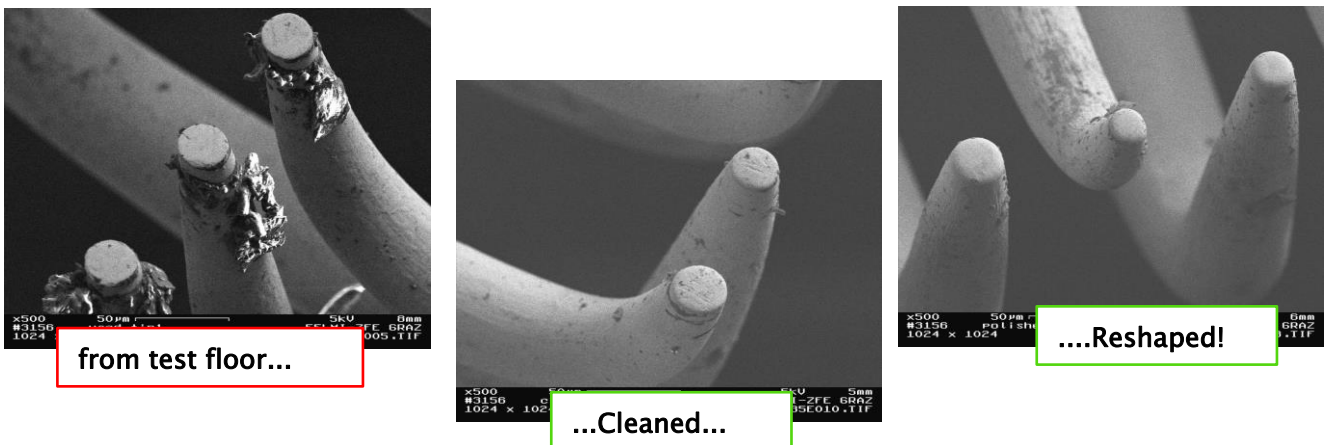
High Pin Count Vertical Probe Cards



Power Probes



Cantilever Probes



New Model TPR-HD "Heavy Duty":

- "Heavy Duty" design with granite stage for high pincount cards – up to 400 N reshaping force
- "contact-less" probe tip sensor. A high precision – low force mechanical sensor detects the probe tips
- process log and probe card log capability
- fully network capable
- process options:
 - Vertical probe cards: cleaning, reshaping, flattening – tip diameter control
 - Cantilever cards: cleaning, reshaping, flattening – tip diameter control
- ESD protected and clean room safe machine table with protection cover to reduce machine noise and full safety featured.

Features:

- Cantilever and Vertical probecards: probe pitch from 30 μm , tip diameter from 10 microns, probe materials: W, WRe, CuBe, Paliney alloys, Rhodium alloys
- cleaning/reshaping for vertical probe cards
- reshaping method based on specifically formulated abrasive reshaping and lapping pads
- highly polished probe surfaces after reshaping (surface roughness < 0.3 microns)
- very good contact resistance after reshaping
- maintains probecard alignment integrity, no realignment due to reshaping process necessary
- fully automatic, no specific operator skills required
- short process times: 1 to 60 minutes

Probe Card Analyzer Test Results

